AMENDMENT OF SOLICITAT	ION/MOD	IFICATION OF	·	****		1 1
2. AMENDMENT/MODIFICATION NO.	3. EFFE	ECTIVE DATE 4	. REQUISITION/PURCHASE R	EQ. NO.	5. PROJECT NO). (If applicable)
0002	03	SEP 22	96000 /321	94155		
6. ISSUED BY	DDE N6	55540	7. ADMINISTERED BY (If other than item 6) CODE			
NSWC CARDEROCK DIVISION 5001 S. BROAD STREET, COPHILADELPHIA PRBUYER/SYMBOL: L. STIEMKE PHONE NO. 2/5-897-/35	4 19112- E					
8. NAME AND ADDRESS OF CONTRACTOR (No.,si		State and ZIP Code)	L	(X) 9A. AMENDA	MENT OF SOLICITA	TION NO.
					0-03-Q-06	16
				9B. DATED (SEE ITEM 11)	
			-	03 SI	CATION OF CONT	BACT/ORDER
				NO.		
				10B. DATED	(SEE ITEM 13)	
CODE	FAC	CILITY CODE				
11. THIS	ITEM ONL	Y APPLIES TO AN	ENDMENTS OF SOLIC	CITATIONS		
X The above numbered solicitation is amended		hand 4. The hand	and data anadising for receipt	of Office	X	ed is not ex
The above numbered solicitation is amended tended.	as set forth in	item 14. The nour a	and date specified for receipt of	or Otters	is extend	ed, LJ is not ex-
Offers must acknowledge receipt of this amendmen						
(a) By completing items 8 and 15, and returning		pies of the amendment; (b) By acknowledging receipt of	of the amendment	on each copy of th	e offer
submitted; or (c) By separate letter or telegram whi MENT TO BE RECEIVED AT THE PLACE DESIGNATION OF THE PLACE DESIGNATIO						
IN REJECTION OF YOUR OFFER. If by virtue of the or letter, provided each telegram or letter makes reference.	is amendment	you desire to change an	offer already submitted, such (change may be ma	de by telegram	
		ilcitation and this amendi	nent, and is received prior to	the opening flour a	ind date specified.	
12. ACCOUNTING AND APPROPRIATION DATA (I	f required)					
13 THIS ITE	M APPLIES	ONLY TO MODIE	CATION OF CONTRAC	TS/ORDERS		
			NO. AS DESCRIBED I			
(X) A. THIS CHANGE ORDER IS ISSUED PURSU					IE CON-	
TRACT ORDER NO. IN ITEM 10A.						
B. THE ABOVE NUMBERED CONTRACT/OR	DER IS MODIFI	IED TO REFLECT THE AL	MINISTRATIVE CHANGES (s	uch as changes in	paving office.	
appropriation data, etc.) SET FORTH IN I				.	, , , , , ,	
C. THIS SUPPLEMENTAL AGREEMENT IS EI	NTERED INTO I	PURSUANT TO AUTHOR	ITY OF:			
D. OTHER (Specify type of modification and	authority)					
E. IMPORTANT: Contractor is a	not. 🗍 i	ia raquirad ta aign t	his document and retu			avian affica
14. DESCRIPTION OF AMENDMENT/MODIFICATION					opies to the is	suing office.
	on (organizou)	o, oo oodon naaango,	moleculary sometration/contract	i sabject matter w.	icic icasibic;	
1) THE DUE DATE FOR RE	CEIPT O	F QUOTATIONS	IS CHANGED TO	24 SEPTEM	BER 2003.	
2) RESPONSES TO QUESTI	ONS ARE	ATTACHED				
Except as provided herein, all terms and conditions	of the docume	ent referenced in Item 9A	or 10A, asheretofore change	d, remains unchan	ged and in full force	9
and effect. 15A NAME AND TITLE OF SIGNER (Type or print			164 NASAE AND THE CO	CONTRACTOR	DEFICED (T	
TO ACTIVE AND THEE OF SIGNER (Type or print	ı		16A. NAME AND TITLE OF	- CONTRACTING (DEFICER (Type or p	rint)
15B CONTRACTOR/OFFEROR	·····	15C DATE CICNED	16B LINITED CTATES OF	ANACDIOA		1400 0477 0101-
TOD CONTINUE ON OUT FERON		15C. DATE SIGNED	16B. UNITED STATES OF	AWERICA		16C. DATE SIGNED
(Signature of person authorized to s	ign)		BY(Signature	of Contracting Off	icer)	
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RESPONSES TO QUESTIONS FOR RFQ N65540-03-Q-0616

We are preparing a bid on the referenced solicitation and have encountered a problem with the drawings. A number of the military specification integrated circuits called out on the parts list are either quite old or obsolete. In particular, U2/U3 and U4/U7 call for M38510/12802BCX and M38510/10504BEX, respectively. The parts list also shows the commercial equivalents for the MS parts, AD584TH for U2-3 and H15043 for U4 and U7. Are these parts acceptable for this project, assuming the device package is the same? Incidentally, the commercial equivalent for U4/U7 is probably IH5043 rather than HI5043 as shown.

Response: Commercial equivalents can be used as long as they cover the full military temperature range -55C to +125C:

The AD584Th is available from Analog Devices.

The IH5043MJE is available from Maxim IC.

- 1) There is an opportunity to remake the board to replace the obsolete components would using SMD technology be acceptable? This only means that the parts would become surface mount. We are planning on no value changes whatsoever. (not broke; don't fix it) Response: Through-hole is preferred, SMD would change the current repair philosophy.
 - 2) There is no test equipment specified. How will I get a first article tested? Response: Test plans for both boards are attached, a simple test fixture is detailed in the test plans.
 - 3) Can the tester be GFE'd to Alpha Beta Tech (ABT). and witnessed at our location? Response: See (2).
 - 4) Do the cards need to be conformal coated? Should we plan on testing them and then coating them (our usual practice)? This requires several shipment iterations. Response: No conformal coating
 - 5) Would a 4 layer card construction be allowed/considered? It does not raise the cost of production significantly and the performance benefits would outweigh any delta in cost. Response: Why? To do a new layout of the board can only drive the per unit cost.

RESPONSES TO QUESTIONS FOR RFQ N65540-03-Q-0616 (CONTINUED)

- 6) In researching the parts ABT has found that industrial temperature parts are significantly lower cost than the military grade parts. Not knowing the application of the units makes me ask if the industrial grade parts would be satisfactory? Response: Mil temp rated parts must be used.
- 7) We can derate the SMD components by using the next larger package size (0805=1/10W to 1206=1/8W) without any cost penalty in these sizes. At the 1210 packages (1/4W) going to 1812 packages does pose a 2 to 1 cost increase. The question is what is the operating temperatures for us to determine the SMD derating which is necessary? Response: No SMD components.

TEST REQUIREMENT SPECIFICATION FOR THE AN/BRR-6 DEPTH CANISTER PRINTED CIRCUIT CARD ASSEMBLY 53711 – 7534911

NAVAL SURFACE WARFARE CENTER CARDEROCK DIVISION, SSES CODE 962

SEPTEMBER 20, 2003

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1.0 SCOPE

This document covers the alignment and test of the Depth Canister PCB Assemblies (2A4A1) for the AN/BRR-6 Part Number 7534911.

2.0 STATIC FREE STATION REQUIREMENTS

The Depth Canister PCB Assembly incorporates static sensitive devices as part of its internal circuitry. Critical safeguard and precautions must be taken to protect the Depth Card from electrostatic discharge damage. A static free workstation must be utilized while testing this device.

3.0 REQUIRED TEST EQUIPMENT

Equipment

<u>Type</u>

Power Supply

+36VDC

(2) 6 ½ Digit DVM's

HP34401A or Equivalent

Test Leads

4.0 PROCEDURE

4.1 Power Supply Adjustment

Connecting only the DVM to the power supply output, adjust the power supply for an output of $+36.0 \pm 1$ V.

4.2 PCB Current Draw

With the power supply turned off, connect the Depth Canister PCB to the test fixture and power supply as shown in Figure 1. Turn on the power supply, measure and record the current draw. Current should be less than 200 mA.

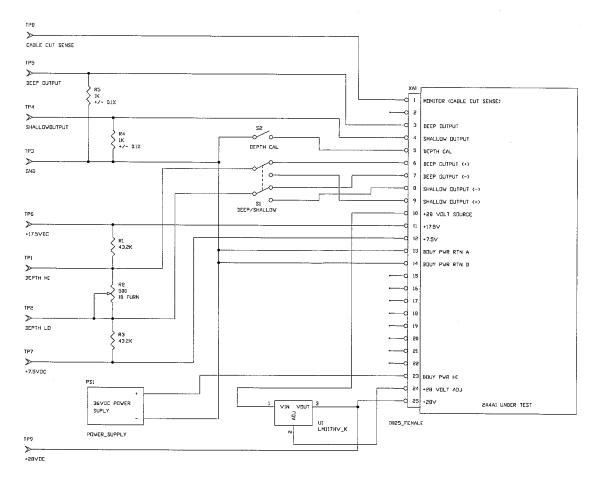


Figure 1. Test Setup

4.3 Voltage Regulators

Using the DVM, check the voltages at the following Test Points.

ME	ΓER			
+ Lead	-Lead	Measured	Spec.	Function
TP9	TP3		+29.8V ± 1.5V	+28V REGULATOR
TP7	TP3		$+7.5V \pm 0.75V$	+7.5V REGULATOR
TP6	TP7		$+10V \pm 0.035V$	+10V XDCR PWR
TP8	TP3		+7.5V ± 0.75V	CABLE CUT SENSE

4.4 Shallow Depth Bias Offset Adjustment

Connect DVM #1 between TP1 and TP2. Connect DVM #2 between TP4 and TP3. Set switch S1 to the SHALLOW position. Set switch S2 to OPEN. Adjust potentiometer R2 of the test fixture for a $0.000 \text{mV} \pm 0.010 \text{mV}$ reading on DVM #1. Adjust depth card potentiometer R15 until a reading of $0.500 \text{V} \pm 0.0125 \text{V}$ is obtained on DVM #2.

4.4.1 Shallow Depth Performance Test

Adjust potentiometer R2 of the test fixture for inputs according to Table 1 (measured on DVM #1). Measure and record the outputs on DVM #2.

4.42 Shallow Depth CAL

Close switch S2. Measure and record the output on DVM #2. The output voltage should be 2.500 \pm .030 V. Open switch S2.

Shallow Depth CAL. Measured:

Table 1
Shallow Depth Performance Test

PSI	FEET	INPUT	OUTPUT	TOLERANCE	MEASURED
		± 0.010 mV			
0.0	0	0.000 mV	0.500 V	<u>+</u> 12.5 mV	V
2.22	5	2.000 mV	0.750 V	<u>+</u> 12.5 mV	v
4.43	10	4.000 mV	1.000 V	<u>+</u> 12.5 mV	V
6.65	15	6.000 mV	1.250 V	<u>+</u> 12.5 mV	v
8.86	20	8.000 mV	1.500 V	<u>+</u> 12.5 mV	V
11.08	25	10.000 mV	1.750 V	<u>+</u> 12.5 mV	V
13.29	30	12.000 mV	2.000 V	<u>+</u> 12.5 mV	V
15.51	35	14.000 mV	2.250 V	±12.5 mV	V
17.72	40	16.000 mV	2.500 V	<u>+</u> 12.5 mV	V
19.94	45	18.000 mV	2.750 V	<u>+</u> 12.5 mV	V
22.15	50	20.000 mV	3.00 V	<u>+</u> 12.5 mV	V

4.5 Deep Depth Bias Offset Adjustment

Connect DVM #1 between TP1 and TP2. Connect DVM #2 between TP5 and TP3. Set switch S1 to the DEEP position. Set switch S2 to OPEN. Adjust potentiometer R2 of the test fixture for a $0.000 \text{mV} \pm 0.010 \text{mV}$ reading on DVM #1. Adjust depth card potentiometer R16 until a reading of $0.500 \text{V} \pm 0.0125 \text{V}$ is obtained on DVM #2.

4.5.1 Deep Depth Performance Test

Adjust potentiometer R2 of the test fixture for inputs according to Table 2 (measured on DVM #1). Measure and record the outputs on DVM #2.

4.52 Deep Depth CAL

Close switch S2. Measure and record the output on DVM #2. The output voltage should be 3.000 \pm .030 V. Open switch S2.

Deep Depth CAL.	Measured:	
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Table 2
Deep Depth Performance Test

PSI	FEET	INPUT <u>+</u> 0.010 mV	OUTPUT	TOLERANCE	MEASURED
0.0	0	0.000 mV	0.500 V	<u>+</u> 12.5 mV	V
44.3	100	3.000 mV	0.750 V	<u>+</u> 12.5 mV	V
88.6	200	6.000 mV	1.000 V	<u>+</u> 12.5 mV	v
132.9	300	9.000 mV	1.250 V	<u>+</u> 12.5 mV	V
177.2	400	12.000 mV	1.500 V	<u>+</u> 12.5 mV	V
221.5	500	15.000 mV	1. 7 50 V	<u>+</u> 12.5 mV	V
265.8	600	18.000 mV	2.000 V	<u>+</u> 25.0 mV	V
310.1	700	21.000 mV	2.250 V	<u>+</u> 25.0 mV	v
354.4	800	24.000 mV	2.500 V	<u>+</u> 25.0 mV	V
398.7	900	27.000 mV	2.750 V	<u>+</u> 25.0 mV	v
443.0	1000	30.000 mV	3.000 V	<u>+</u> 25.0 mV	V

TEST REQUIREMENT SPECIFICATION FOR THE AN/BRR-6B DEPTH CANISTER PRINTED CIRCUIT CARD ASSEMBLY 53711 – 7534928

NAVAL SURFACE WARFARE CENTER CARDEROCK DIVISION, SSES CODE 962

SEPTEMBER 20, 2003

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1.0 **SCOPE**

This document covers the alignment and test of the Depth Canister PCB Assemblies (2A4A1) for the AN/BRR-6B Part Number 7534928.

STATIC FREE STATION REQUIREMENTS

The Depth Canister PCB Assembly incorporates static sensitive devices as part of its internal circuitry. Critical safeguard and precautions must be taken to protect the Depth Card from electrostatic discharge damage. A static free workstation must be utilized while testing this device.

3.0 REQUIRED TEST EQUIPMENT

Equipment Power Supply (2) 6 ½ Digit DVM's

Type +36VDC

HP34401A or Equivalent

Test Leads

4.0 **PROCEDURE**

4.1 Power Supply Adjustment

Connecting only the DVM to the power supply output, adjust the power supply for an output of $+36.0 \pm 1$ V.

4.2 PCB Current Draw

With the power supply turned off, connect the Depth Canister PCB to the test fixture and power supply as shown in Figure 1. Turn on the power supply, measure and record the current draw. Current should be less than 200 mA.

+36 Volt Current.	Measured:	
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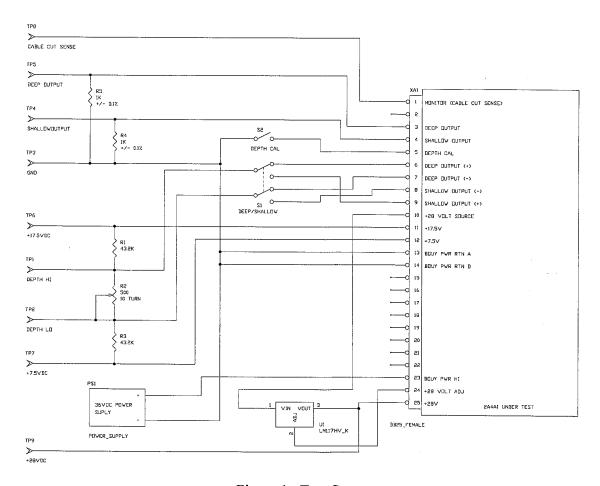


Figure 1. Test Setup

4.3 Voltage Regulators

Using the DVM, check the voltages at the following Test Points.

MET	TER			
+ Lead	-Lead	Measured	Spec.	Function
TP9	TP3		+29.8V ± 1.5V	+28V REGULATOR
TP7	TP3		$+7.5V \pm 0.75V$	+7.5V REGULATOR
TP6	TP7		$+10V \pm 0.035V$	+10V XDCR PWR
TP8	TP3		+7.5V ± 0.75V	CABLE CUT SENSE

4.4 Shallow Depth Bias Offset Adjustment

Connect DVM #1 between TP1 and TP2. Connect DVM #2 between TP4 and TP3. Set switch S1 to the SHALLOW position. Set switch S2 to OPEN. Adjust potentiometer R2 of the test fixture for a $0.000 \text{mV} \pm 0.010 \text{mV}$ reading on DVM #1. Adjust depth card potentiometer R15 until a reading of $1.500 \text{V} \pm 0.0125 \text{V}$ is obtained on DVM #2.

4.4.1 Shallow Depth Performance Test

Adjust potentiometer R2 of the test fixture for inputs according to Table 1 (measured on DVM #1). Measure and record the outputs on DVM #2.

4.42 Shallow Depth CAL

Close switch S2. Measure and record the output on DVM #2. The output voltage should be $3.500 \pm .030$ V. Open switch S2.

Shallow Depth CAL. Measured:

Table 1
Shallow Depth Performance Test

PSI	FEET	INPUT	OUTPUT	TOLERANCE	MEASURED
		$\pm 0.010 \text{mV}$			
0.0	0	0.000 mV	1.500 V	<u>+</u> 12.5 mV	V
4.43	10	4.000 mV	2.000 V	<u>+</u> 12.5 mV	V
8.86	20	8.000 mV	2.500 V	<u>+</u> 12.5 mV	V
13.29	30	12.000 mV	3.000 V	<u>+</u> 12.5 mV	V
17.72	40	16.000 mV	3.500 V	<u>+</u> 12.5 mV	V
22.15	50	20.000 mV	4.000 V	<u>+</u> 12.5 mV	V
26.58	60	24.000 mV	4.500 V	<u>+</u> 25.0 mV	V
31.01	70	28.000 mV	5.000 V	<u>+</u> 25.0 mV	V
35.44	80	32.000 mV	5.500 V	<u>+</u> 25.0 mV	V
39.87	90	36.000 mV	6.000 V	<u>+</u> 25.0 mV	V
44.30	100	40.000 mV	6.500 V	<u>+</u> 25.0 mV	V

4.5 Deep Depth Bias Offset Adjustment

Connect DVM #1 between TP1 and TP2. Connect DVM #2 between TP5 and TP3. Set switch S1 to the DEEP position. Set switch S2 to OPEN. Adjust potentiometer R2 of the test fixture for a $0.000 \text{mV} \pm 0.010 \text{mV}$ reading on DVM #1. Adjust depth card potentiometer R16 until a reading of $1.500 \text{V} \pm 0.0125 \text{V}$ is obtained on DVM #2.

4.5.1 Deep Depth Performance Test

Adjust potentiometer R2 of the test fixture for inputs according to Table 2 (measured on DVM #1). Measure and record the outputs on DVM #2.

4.52 Dèep Depth CAL

Close switch S2. Measure and record the output on DVM #2. The output voltage should be $6.500 \pm .030$ V. Open switch S2.

Deep Depth CAL.	Measured:	

Table 2
Deep Depth Performance Test

PSI	FEET	INPUT + 0.010 mV	OUTPUT	TOLERANCE	MEASURED
0.0	0	0.000 mV	1.500 V	<u>+</u> 12.5 mV	V
44.3	100	3.000 mV	2.000 V	<u>+</u> 12.5 mV	V
88.6	200	6.000 mV	2.500 V	<u>+</u> 12.5 mV	v
132.9	300	9.000 mV	3.000 V	<u>+</u> 12.5 mV	V
177.2	400	12.000 mV	3.500 V	<u>+</u> 12.5 mV	V
221.5	500	15.000 mV	4.000 V	<u>+</u> 12.5 mV	V
265.8	600	18.000 mV	4.500 V	<u>+</u> 25.0 mV	V
310.1	700	21.000 mV	5.000 V	<u>+</u> 25.0 mV	V
354.4	800	24.000 mV	5.500 V	<u>+</u> 25.0 mV	V
398.7	900	27.000 mV	6.000 V	<u>+</u> 25.0 mV	v
443.0	1000	30.000 mV	6.500 V	<u>+</u> 25.0 mV	V